Session Program

17-19 Nov 2021



The 39th RD50 Workshop (Valencia) Defect and Material Characterization

ADEIT Plaza Virgen de la Paz, 3. 46001 Valencia, Spain

Wednesday 17 November

09:20

Defect and Material Characterization Session | Location: ADEIT, Plaza Virgen de la Paz, 3. 46001 Valencia, Spain | Convener: Michael Moll 09:20-09:40 Development of 2D GaN and 3D SiC detectors **Speakers** Prof. Hongwei Liang, Dr XIn Shi, Dr Xiaochuan Xia, Dr Zhengzhong Zhang 09:40-10:00 Test results of the first 4H-SiC LGAD from NJU China **Speakers** Dr Tao Yang, Dr Qing Liu 10:00-10:20 Non-Ionizing Energy Loss: Geant4 simulations towards more advanced NIEL concept for radiation damage modelling and prediction Speaker Vendula Subert 10:20-10:40 Study of gamma irradiated p-type silicon diodes with different resistivities Iveta Zatocilova 10:40-11:00 Update on radiation damage investigation of epitaxial p-type silicon using Schottky and pn-junction diodes Speaker Christoph Thomas Klein 11:00-11:30 Coffee Break 11:30-11:50 Defect characterization studies on highly irradiated Low Gain Avalanche Detectors Speaker Anja Himmerlich 11:50-12:10 Investigation of the BiOi defect in EPI and Cz silicon diodes using Thermally Stimulated current (TSC) and Thermally Stimulated Capacitance (TS-Cap) Speaker Mr Chuan Liao 12:10-12:40 Discussion: Defect Studies & New Materials **Speakers**

12:40

Ioana Pintilie, Michael Moll